Docket No.: 51876P551

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

Su-Hwan Oh, et al.

Application No.:

Filed:

For: Widely Tunable Sampled-Grating

Distributed Feedback Laser Diode

Art Group:

Examiner:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, enclosed is a copy of Information Disclosure Statement by Applicant (form PTO/SB/08), which is being submitted concurrently with the Utility Application. It is respectfully requested that the cited references be considered and that the enclosed copy of PTO/SB/08 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s).

-1- 51876P551

The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Please charge any fees due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Eric S. Hyman, Reg No

Date: /1/3409

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Substitute for form 1449A/PTO		Complete if Known		
		Application Number		
INFORMATION DISCLOSURE			Filing Date	
STATEMENT BY APPLICANT (use as many sheets as necessary)			First Named Inventor	Su-Hwan Oh
			Art Unit	
	1		Examiner Name	
Sheet	0	f	Attorney Docket Number	51876P551

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Document Number Number - Kind Code ² (if known)	Publication Date or Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-5784183	07-21-1998	Aoki et al.	
		US-		·	
		US-			
		US-	*		
		US-			

	FOREIGN PATENT DOCUMENTS							
Examiner C	Cite	Foreign Patent Document	5		Pages, Columns, Lines,	те		
Initials*	No.¹	Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)	Publication Date Name of Patentee or MM-DD-YYYY Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Is		
		07-273400	10-25-1995	Nippon Telegr & Teleph Corp.				

Examiner	Date	
Signature	Considered	
Digitature	Considered	

Based on PTO/SB/08A (08-03) as modified by Blakely, Solokoff, Taylor & Zafman (wir) 08/11/2003.

^{*}Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Substitute for form 1449A/PTO		Complete if Kn wn		
		Application Number		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Filing Date	
			First Named Inventor	Su-Hwan Oh
			Art Unit	
(use as many sneets as necessary)		Examiner Name		
Sheet	of	F	Attorney Docket Number	51876P551

NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No.1 Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		"Asymmetric Sampled Grating Laser Array for a Multiwavelength WDM Source", S. Ryu, et al., 2002 IEEE, Vol., 14, No. 2, Dec. 2002, pgs 1656-1658				
Examiner	•	Date				

Examiner	Date	
Signature	Considered	

^{*}ExamIner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

¹Applicant's unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.

Information Disclosure Statement

New U.S. Patent Application for WIDELY TUNABLE SAMPLED-GRATING DISTRIBUTED FEEDBACK LASER DIODE Our Ref. No.: P03E5009/US/jk

Reference No.:

- (1) US Patent No. 5,784,183
- (2) JP Laid-Open No. 7-273400
- (3) Asymmetric Sampled Grating Laser Array for a Multiwavelength WDM Source (IEEE PHOTONICS TECHNOLOGY LETTERS, VOL. 14, NO. 12, DECEMBER 2002, PAGES 1656-1658)